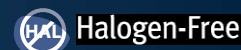


## EPC2090 – Enhancement Mode Power Transistor

 $V_{DS}$ , 100 V $R_{DS(on)}$ , 5.2 mΩ max $I_D$ , 125 A

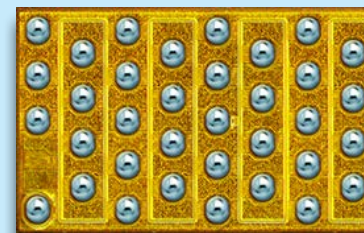
Revised December 19, 2024

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

**Application Notes:**

- Easy-to-use and reliable gate, Gate Drive ON = 5 V typical, OFF = 0 V (negative voltage not needed)
- Top of FET is electrically connected to source

Questions:  
Ask a GaN  
Expert



Die Size: 2.3 x 1.45 mm

**EPC2090** eGaN® FETs are supplied in passivated die form with copper pillars.

**Applications**

- Copper Pillars for Package Integration
- DC-DC Converters
- Isolated DC-DC Converters
- Lidar
- Sync Rectification for AC-DC and DC-DC
- Point-of-Load Converters
- USB-C
- Class-D Audio
- LED Lighting
- eMobility

**Benefits**

- Ultra High Efficiency
- No Reverse Recovery
- Ultra Low  $Q_G$
- Small Footprint

**Maximum Ratings**

PARAMETER		VALUE	UNIT
$V_{DS}$	Drain-to-Source Voltage (Continuous)	100	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150 °C)	120	
$I_D$	Continuous ( $T_J \leq 125^\circ\text{C}$ )	46	A
	Pulsed ( $25^\circ\text{C}$ , $T_{PULSE} = 300 \mu\text{s}$ )	125	
$V_{GS}$	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
$T_J$	Operating Temperature	-40 to 150	$^\circ\text{C}$
$T_{STG}$	Storage Temperature	-40 to 150	

**Thermal Characteristics**

PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Case TOP)	1.07	$^\circ\text{C/W}$
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board (Case BOTTOM)	2.9	

**Static Characteristics ( $T_J = 25^\circ\text{C}$  unless otherwise stated)**

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 0.045 \text{ mA}$	100			V
$I_{DSS}$	Drain-Source Leakage	$V_{GS} = 0 \text{ V}$ , $V_{DS} = 80 \text{ V}$		0.004	0.045	mA
	Drain-Source Leakage	$V_{GS} = 0 \text{ V}$ , $V_{DS} = 80 \text{ V}$ , $T_J = 90^\circ\text{C}$		0.02	0.17	
$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		0.01	1.5	
	Gate-to-Source Forward Leakage <sup>#</sup>	$V_{GS} = 5 \text{ V}$ , $T_J = 125^\circ\text{C}$		0.3	4	
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		0.03	4	
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 4.2 \text{ mA}$	0.8	1.1	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$ , $I_D = 16 \text{ A}$		3.8	5.2	mΩ
$V_{SD}$	Source-Drain Forward Voltage <sup>#</sup>	$I_S = 0.5 \text{ A}$ , $V_{GS} = 0 \text{ V}$		1.5		V

<sup>#</sup> Defined by design. Not subject to production test.

Dynamic Characteristics<sup>#</sup> ( $T_J = 25^\circ\text{C}$  unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$C_{ISS}$	Input Capacitance	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		1046	1328	pF
$C_{RSS}$	Reverse Transfer Capacitance			2.9		
$C_{OSS}$	Output Capacitance			364	478	
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 1)	$V_{DS} = 0\text{ to }50\text{ V}, V_{GS} = 0\text{ V}$		441		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 2)			548		
$R_G$	Gate Resistance			0.4		$\Omega$
$Q_G$	Total Gate Charge	$V_{DS} = 50\text{ V}, V_{GS} = 5\text{ V}, I_D = 16\text{ A}$		7.3	9.3	nC
$Q_{GS}$	Gate-to-Source Charge	$V_{DS} = 50\text{ V}, I_D = 16\text{ A}$		2.8		
$Q_{GD}$	Gate-to-Drain Charge			0.7		
$Q_{G(TH)}$	Gate Charge at Threshold			2.1		
$Q_{OSS}$	Output Charge	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		27	35	
$Q_{RR}$	Source-Drain Recovery Charge			0		

<sup>#</sup> Defined by design. Not subject to production test.

All measurements were done with substrate connected to source.

Note 1:  $C_{OSS(ER)}$  is a fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Note 2:  $C_{OSS(TR)}$  is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

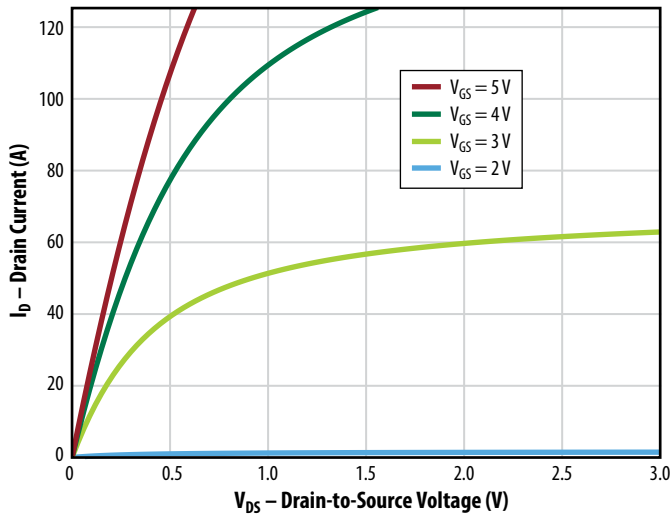
Figure 1: Typical Output Characteristics at  $25^\circ\text{C}$ 

Figure 2: Typical Transfer Characteristics

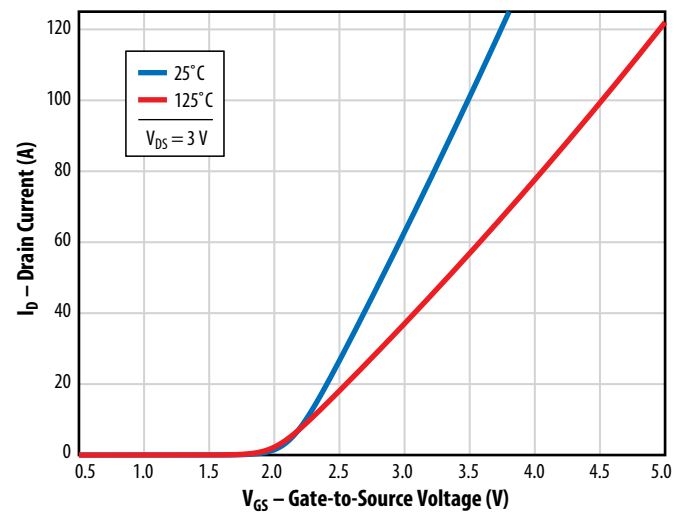
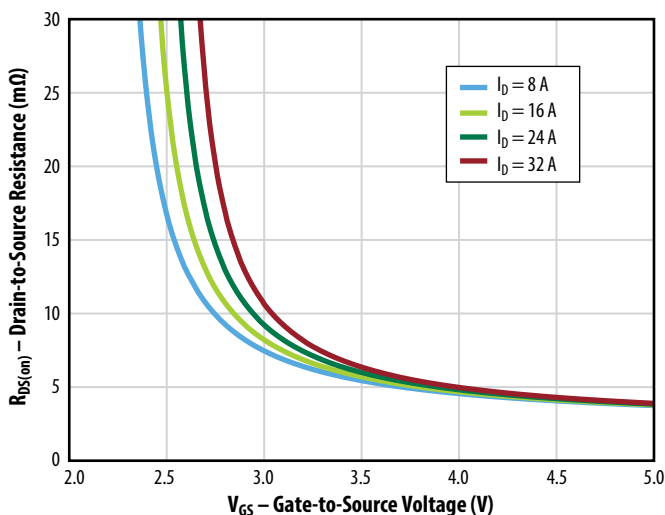
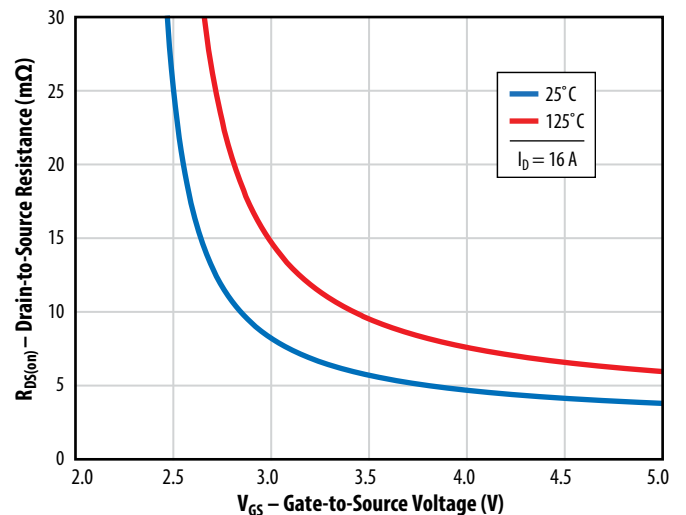
Figure 3:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Drain CurrentsFigure 4: Typical  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Temperatures

Figure 5a: Typical Capacitance (Linear Scale)

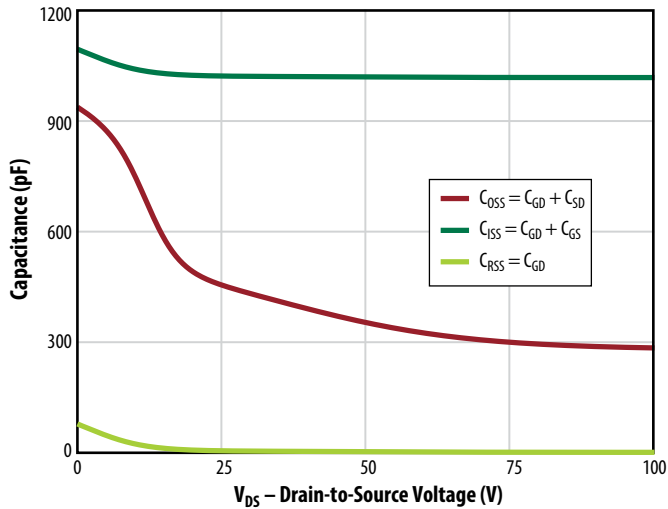


Figure 5b: Typical Capacitance (Log Scale)

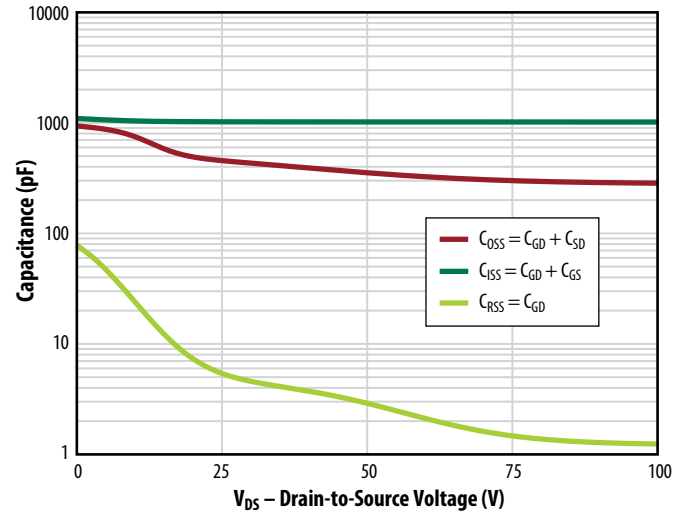
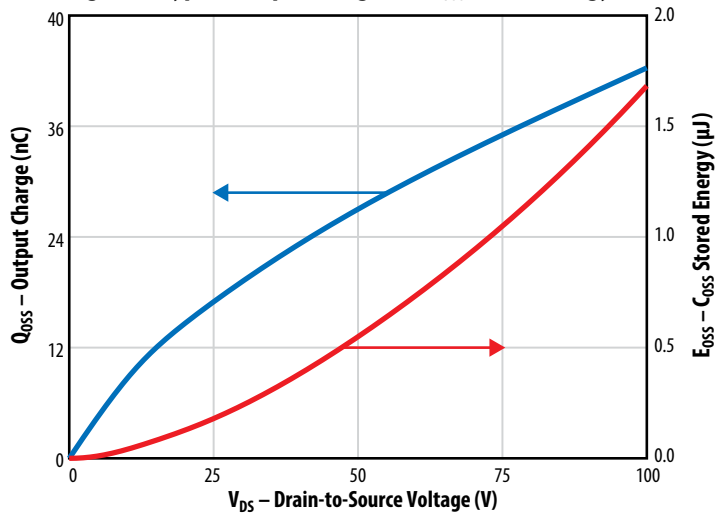
Figure 6: Typical Output Charge and  $C_{OSS}$  Stored Energy

Figure 7: Typical Gate Charge

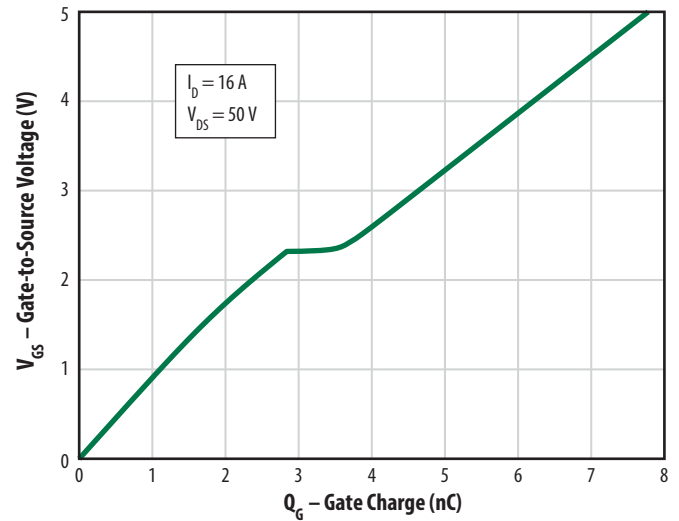
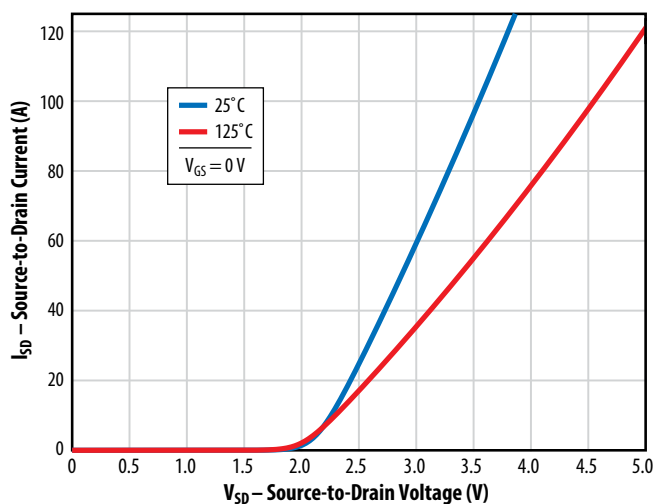


Figure 8: Reverse Drain-Source Characteristics



**Note:** Negative gate drive voltage increases the reverse drain-source voltage.  
EPC recommends 0 V for OFF.

Figure 9: Normalized On-State Resistance vs. Temperature

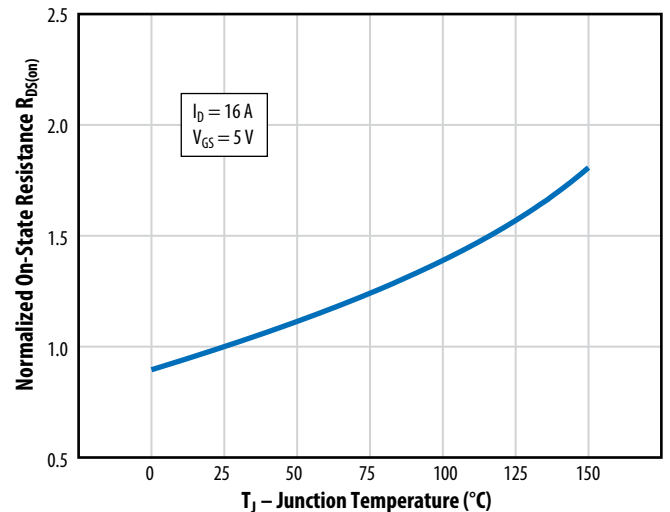


Figure 10: Normalized Threshold Voltage vs. Temperature

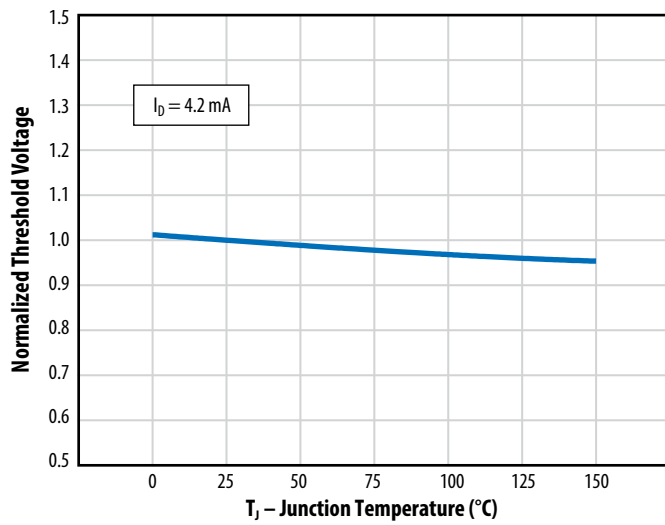


Figure 11: Safe Operating Area

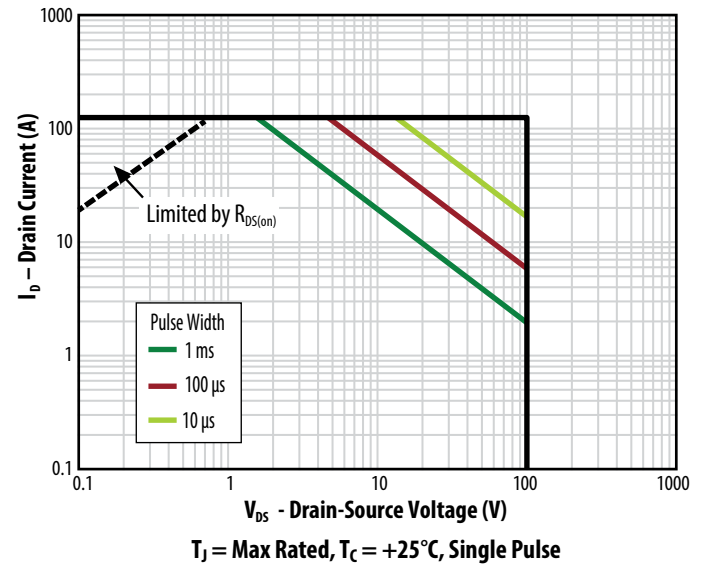
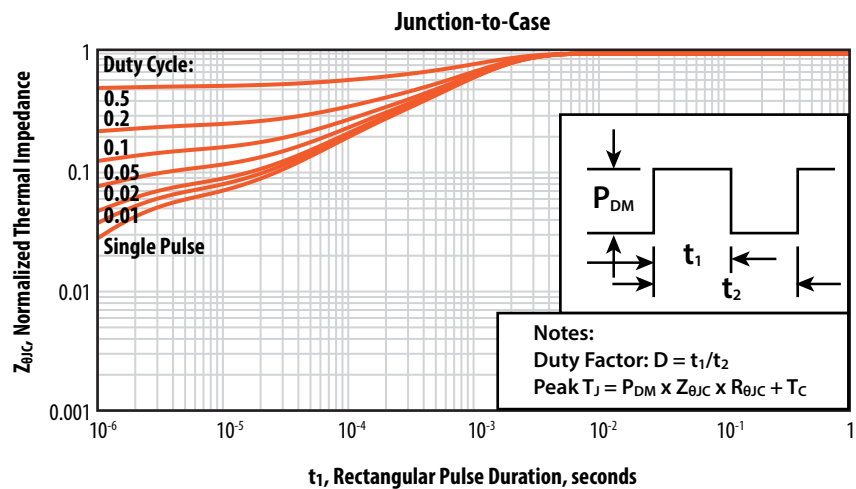
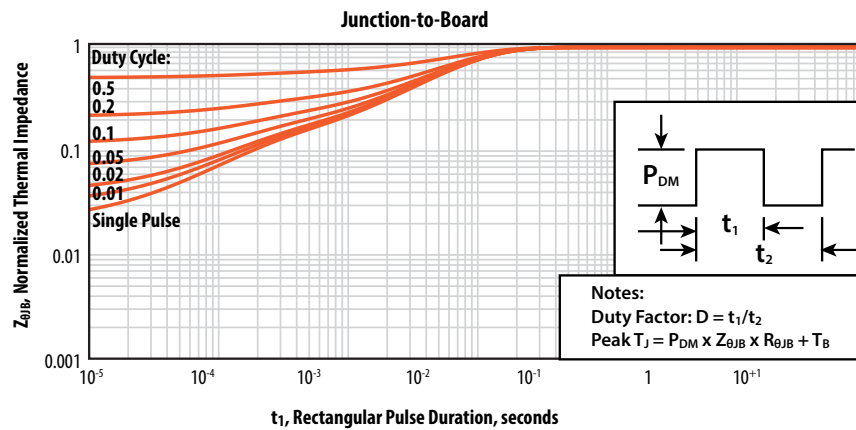


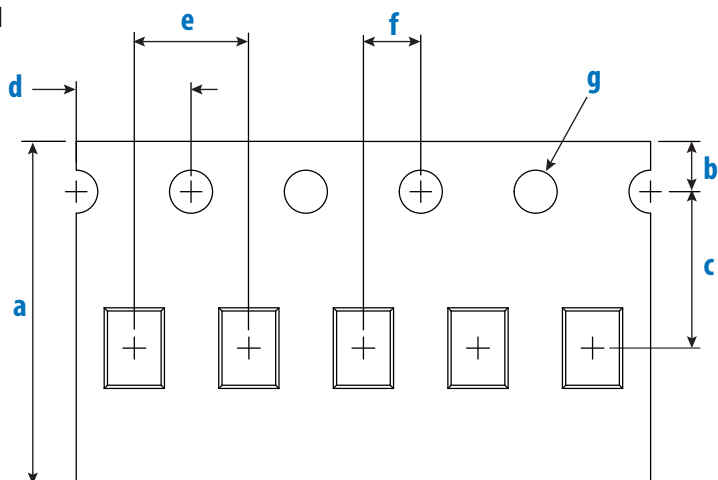
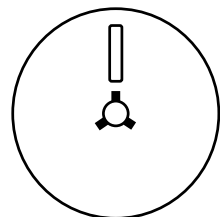
Figure 12: Transient Thermal Response Curves



## TAPE AND REEL CONFIGURATION

4 mm pitch, 8 mm wide tape on 7" reel

7" inch reel



Loaded Tape Feed Direction →



Die orientation dot  
Pin 1 is under this corner

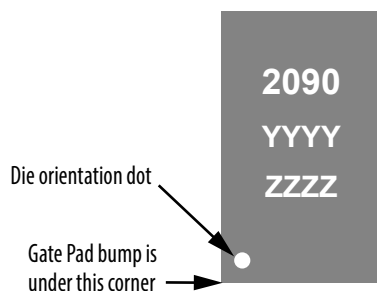
Die is placed into pocket solder bump side down (face side down)

EPC2204A (Note 1)	Dimension (mm)		
	Target	MIN	MAX
<b>a</b>	12.00	11.90	12.30
<b>b</b>	1.75	1.65	1.85
<b>c</b> (Note 2)	5.50	5.45	5.55
<b>d</b>	4.00	3.90	4.10
<b>e</b>	4.00	3.90	4.10
<b>f</b> (Note 2)	2.00	1.95	2.05
<b>g</b>	1.50	1.50	1.60
<b>h</b>	0.50	0.45	0.55

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

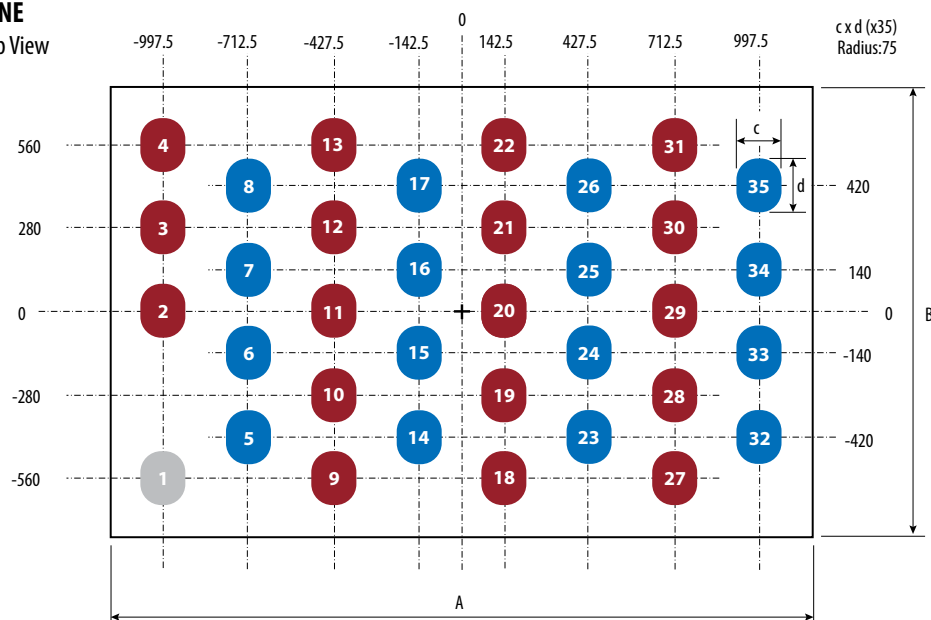
## DIE MARKINGS



Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2090	2090	YYYY	ZZZZ

## DIE OUTLINE

Solder Bump View



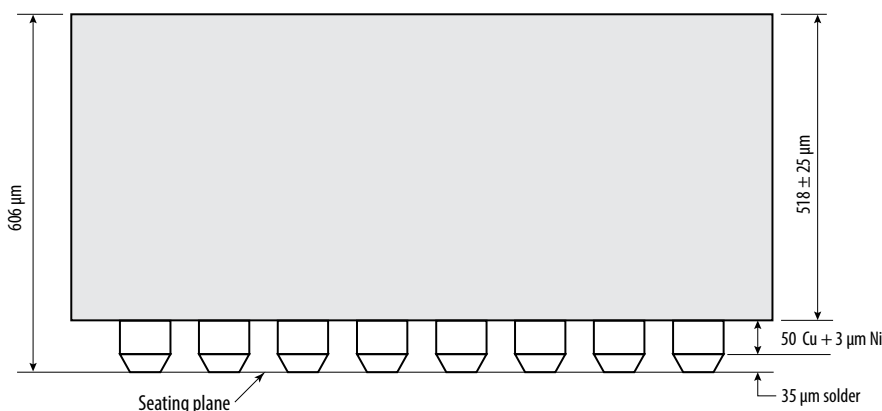
DIM	Micrometers		
	MIN	Nominal	MAX
A	2270	2300	2330
B	1420	1450	1480
c		150	
d		180	

Pad 1 is Gate;

Pads 2-4, 9-13, 18-22, 27-31 are Source;

Pads 5-8, 14-17, 23-26, 32-35 are Drain

Side View



Note: solder cap height is post reflow

## Additional resources available:

- Assembly resources – [https://epc-co.com/epc/Portals/0/epc/documents/product-training/Appnote\\_GaNassembly.pdf](https://epc-co.com/epc/Portals/0/epc/documents/product-training/Appnote_GaNassembly.pdf)
- Library of Altium footprints for production FETs and ICs – <https://epc-co.com/epc/documents/altium-files/EPC%20Altium%20Library.zip>  
(for preliminary device Altium footprints, contact EPC)

**Note:** Cu pillar dies are not intended for mounting on a PCB, they are intended for use in a package. Terms of die usage: The die represented by this data sheet are intended for initial evaluation for integration to buyer defined package. EPC does not guarantee reliability in the buyer specific package. To ensure reliability, the die may need redesign to be optimized to buyers specific package. NRE may apply

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change without notice.

Revised July, 2024